

256 Kbit (32K x 8) nvSRAM with Real Time Clock

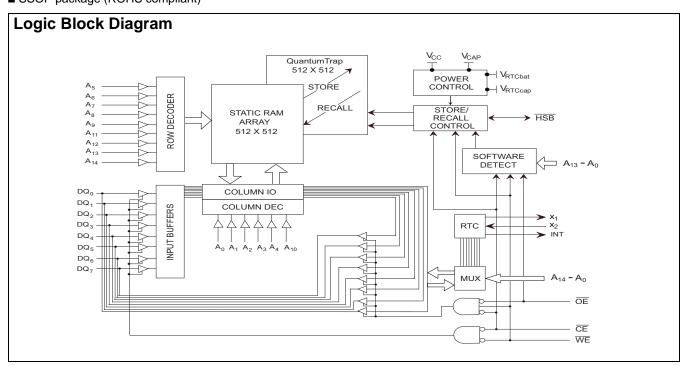
Features

- Data integrity of Cypress nvSRAM combined with full featured real time clock
 - □ Low power, 300 nA Max, RTC current
 - Capacitor or battery backup for RTC
- Watchdog timer
- Clock alarm with programmable interrupts
- 25 ns, 35 ns, and 45 ns access times
- Hands off automatic *STORE* on power down with only a small capacitor
- *STORE* to QuantumTrap[™] initiated by software, device pin, or on power down
- RECALL to SRAM initiated by software or on power up
- Infinite READ, WRITE, and RECALL cycles
- High reliability
 - □ Endurance to 200K cycles
 - □ Data retention: 20 years at 55°C
- 10 mA typical I_{CC} at 200 ns cycle time
- Single 3V operation with tolerance of +20%, -10%
- Commercial and industrial temperature
- SSOP package (ROHS compliant)

Functional Description

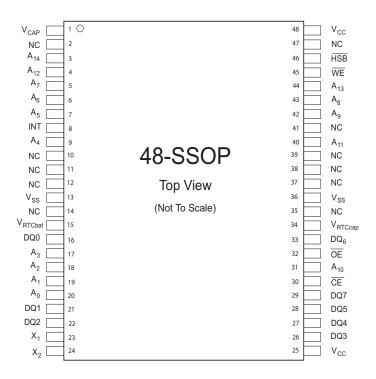
The Cypress CY14B256K combines a 256 Kbit nonvolatile static RAM with a full-featured real time clock in a monolithic integrated circuit. The embedded nonvolatile elements incorporate QuantumTrap technology producing the world's most reliable nonvolatile memory. The SRAM is read and written an infinite number of times, while independent, nonvolatile data resides in the nonvolatile elements.

The real time clock function provides an accurate clock with leap year tracking and a programmable high accuracy oscillator. The alarm function is programmable for one time alarms or periodic seconds, minutes, hours, or days. There is also a programmable watchdog timer for process control.





Pin Configurations



Pin Definitions

Pin Name	IO Type	Description				
A ₀ -A ₁₄	Input	Address Inputs. Used to select one of the 32,768 bytes of the nvSRAM.				
DQ0-DQ7	Input or Output	Bidirectional Data IO lines. Used as input or output lines depending on operation.				
NC	No Connect	No Connects. This pin is not connected to the die.				
WE	Input Write Enable Input, Active LOW. When selected LOW, it enables to write data on the the address location latched by the falling edge of CE.					
CE	Input	Chip Enable Input, Active LOW. When LOW, selects the chip. When HIGH, deselects the chip.				
ŌĒ	OE Input Output Enable, Active LOW. The active LOW OE input enables the data output by read cycles. Deasserting OE high causes the IO pins to tri-state.					
X ₁	Output	Crystal Connection. Drives crystal on start up.				
X ₂	Input	Crystal Connection for 32.768 kHz Crystal.				
V _{RTCcap}	Power Supply	Capacitor Supplied Backup RTC Supply Voltage. (Left unconnected if V _{RTCbat} is used)				
V _{RTCbat}	Power Supply	Battery Supplied Backup RTC Supply Voltage. (Left unconnected if V _{RTCcap} is used)				
INT	Output	Interrupt Output . It is programmed to respond to the clock alarm, the watchdog timer, and the power monitor. Programmable to either active HIGH (push or pull) or LOW (open drain).				
V _{SS}	Ground	Ground for the Device. It is connected to ground of the system.				
V _{CC}	Power Supply	Power Supply Inputs to the Device.				
HSB	Input or Output	Hardware Store Busy (HSB) . When low, this output indicates a Hardware Store is in progress. When pulled low external to the chip, it initiates a nonvolatile STORE operation. A weak internal pull up resistor keeps this pin HIGH if not connected (connection optional).				
V _{CAP}	Power Supply	AutoStore Capacitor . Supplies power to nvSRAM during power loss to store data from SRAM to nonvolatile elements.				

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Device Operation

The CY14B256K nvSRAM consists of two functional components paired in the same physical cell. The components are SRAM memory cell and a nonvolatile QuantumTrap cell. The SRAM memory cell operates as a standard fast static RAM. Data in the SRAM transfers to the nonvolatile cell (the STORE operation) or from the nonvolatile cell to SRAM (the RECALL operation). This architecture enables all cells to store and recall in parallel. During the STORE and RECALL operations, SRAM READ and WRITE operations are inhibited. The CY14B256K supports infinite reads and writes similar to a typical SRAM. In addition, it provides infinite RECALL operations from the nonvolatile cells and up to 200,000 STORE operations.

SRAM Read

The CY14B256K performs a READ cycle whenever $\overline{\text{CE}}$ and $\overline{\text{OE}}$ are LOW while $\overline{\text{WE}}$ and $\overline{\text{HSB}}$ are HIGH. The address specified on pins A₀₋₁₄ determines which of the 32,752 data bytes are accessed. When the READ is initiated by an address transition, the outputs are valid after a delay of t_{AA} (READ cycle #1). If the READ is initiated by $\overline{\text{CE}}$ or $\overline{\text{OE}}$, the outputs are valid at t_{ACE} or at t_{DOE}, whichever is later (READ cycle 2). The data outputs repeatedly respond to address changes within the t_{AA} access time without the need for transitions on any control input pins. They remain valid until another address change or until $\overline{\text{CE}}$ or $\overline{\text{OE}}$ is brought HIGH, or $\overline{\text{WE}}$ or $\overline{\text{HSB}}$ is brought LOW.

SRAM Write

A WRITE cycle is performed whenever CE and WE are LOW and HSB is HIGH. The address inputs are stable prior to entering the WRITE cycle and must remain stable until either CE or WE goes HIGH at the end of the cycle. The data on the common IO pins DQ_{0-7} is written into the memory if the data is valid t_{SD_i} before the end of a WE controlled WRITE or before the end of an CE controlled WRITE. OE is kept HIGH during the entire WRITE cycle to avoid data bus contention on common IO lines. If OE is left LOW, internal circuitry turns off the output buffers t_{HZWE} after WE goes LOW.

AutoStore Operation

The CY14B256K stores data to nvSRAM using one of the three storage operations:

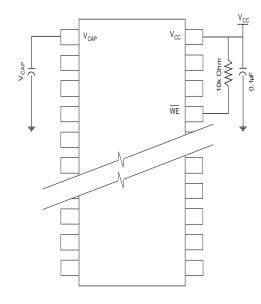
- 1. Hardware store activated by HSB
- 2. Software store activated by an address sequence
- 3. AutoStore on device power down

AutoStore operation is a unique feature of QuantumTrap technology and is enabled by default on the CY14B256K.

During normal operation, the device draws current from V_{CC} to charge a capacitor connected to the V_{CAP} pin. This stored charge is used by the chip to perform a single STORE operation. If the voltage on the V_{CC} pin drops below V_{SWITCH} , the part automatically disconnects the V_{CAP} pin from V_{CC} . A STORE operation is initiated with power provided by the V_{CAP} capacitor.

Figure 1 shows the proper connection of the storage capacitor, V_{CAP} , for automatic store operation. Refer to the " on page 14 for the size of V_{CAP} . The voltage on the V_{CAP} pin is driven to 5V by a charge pump internal to the chip. A pull up is placed on \overline{WE} to hold it inactive during power up.

Figure 1. AutoStore Mode



To reduce unnecessary nonvolatile stores, AutoStore and Hardware Store operations are ignored unless at least one WRITE operation has taken place since the most recent STORE or RECALL cycle. Software initiated STORE cycles are performed regardless of whether a WRITE operation has taken place. The HSB signal is monitored by the system to detect if an AutoStore cycle is in progress.

Hardware STORE (HSB) Operation

The CY14B256K provides the $\overline{\text{HSB}}$ pin for controlling and acknowledging the STORE operations. The HSB pin is used to request a hardware STORE cycle. When the HSB pin is driven low, the CY14B256K conditionally initiates a STORE operation after t_{DELAY}. An actual STORE cycle only begins if a WRITE to the SRAM takes place since the last STORE or RECALL cycle. The HSB pin also acts as an open drain driver that is internally driven low to indicate a busy condition, while the STORE (initiated by any means) is in progress.

SRAM_READ and WRITE operations, that are in progress when HSB is driven low by any means, are given time to complete before the STORE operation is initiated. After HSB goes LOW, the CY14B256K continues SRAM operations for t_{DELAY}, During t_{DELAY}, multiple SRAM <u>READ</u> operations take place. If a WRITE is in progress when HSB is pulled LOW, it allows a time, t_{DELAY}, to complete. However, any SRAM WRITE cycles requested after HSB goes LOW are inhibited until HSB returns HIGH.



During any STORE operation, regardless of how it is initiated, the CY14B256K continues to drive the HSB pin LOW, releasing it only when the STORE is complete. After completing the STORE operation, the CY14B256K remains disabled until the HSB pin returns HIGH.

If HSB is not used, it is left unconnected.

Hardware RECALL (Power Up)

During power up or after any low power condition (V_{CC} is less than V_{SWITCH}), an internal RECALL request is latched. When V_{CC} again exceeds the sense voltage of V_{SWITCH} , a RECALL cycle is automatically initiated and takes $t_{HRECALL}$ to complete.

Software STORE

Data transfers from the SRAM to the nonvolatile memory by a software address sequence. The CY14B256K software STORE cycle is initiated by executing sequential CE controlled READ cycles from six specific address locations in exact order. During the STORE cycle, an erase of the previous nonvolatile data is first performed followed by a program of the nonvolatile elements. When a STORE cycle is initiated, further input and output are disabled until the cycle is completed.

Because a sequence of READs from specific addresses is used for STORE initiation, it is important that no other READ or WRITE accesses intervene in the sequence. If it intervenes the sequence is aborted and no STORE or RECALL takes place.

To initiate the software STORE cycle, the following READ sequence is performed:

- 1. Read address 0x0E38, Valid READ
- 2. Read address 0x31C7, Valid READ
- 3. Read address 0x03E0, Valid READ
- 4. Read address 0x3C1F, Valid READ
- 5. Read address 0x303F, Valid READ
- 6. Read address 0x0FC0, Initiate STORE cycle

The software sequence is clocked with $\overline{\text{CE}}$ controlled READs or $\overline{\text{OE}}$ controlled READs. When the sixth address in the sequence is entered, the STORE cycle commences and the chip is disabled. It is important that READ cycles and not WRITE cycles are used in the sequence. It is not necessary that $\overline{\text{OE}}$ is low for the sequence is valid. After the t_{STORE} cycle time is fulfilled, the SRAM again is activated for READ and WRITE operations.

Software RECALL

Data transfers from the nonvolatile memory to the SRAM by a software address sequence. A software RECALL cycle is initiated with a sequence of READ operations in a manner similar to the software STORE initiation. To initiate the RECALL cycle, the following sequence of $\overline{\text{CE}}$ controlled READ operations is performed:

- 1. Read address 0x0E38, Valid READ
- 2. Read address 0x31C7, Valid READ
- 3. Read address 0x03E0, Valid READ
- 4. Read address 0x3C1F, Valid READ
- 5. Read address 0x303F, Valid READ
- Read address 0x0C63, Initiate RECALL cycle

Internally, RECALL is a two step procedure. First, the SRAM data is cleared and then the nonvolatile information is transferred into the SRAM cells. After the $t_{\mbox{\scriptsize RECALL}}$ cycle time, the SRAM is again ready for READ and WRITE operations. The RECALL operation in no way alters the data in the nonvolatile elements.

Data Protection

The CY14B256K protects data from corruption during low voltage conditions by inhibiting all externally initiated STORE and WRITE operations. The low voltage condition is detected when V_{CC} is less than V_{SWITCH} . If the CY14B256K is in a WRITE mode (both CE and WE are low) at power up after a RECALL or a STORE, the WRITE is inhibited until a negative transition on CE or WE is detected. This protects against inadvertent writes during power up or brown out conditions.

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Table 1. Mode Selection

CE	WE	OE	A13-A0	Mode	Ю	Power
Н	Χ	Χ	Х	Not Selected	Output High Z	Standby
L	Н	L	Х	Read SRAM	Output Data	Active
L	L	Χ	Х	Write SRAM	Input Data	Active
L	Н	L	0x0E38 0x31C7 0x03E0 0x3C1F 0x303F 0x0FC0	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile Store	Output Data Output Data Output Data Output Data Output Data Output Data Output High Z	Active I _{CC2} [1, 2, 3]
L	Н	L	0x0E38 0x31C7 0x03E0 0x3C1F 0x303F 0x0C63	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile Recall	Output Data Output Data Output Data Output Data Output Data Output Data Output High Z	Active ^[1, 2, 3]

Noise Considerations

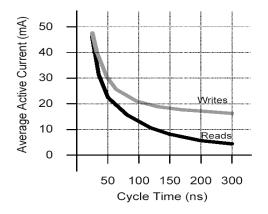
The CY14B256K is a high speed memory. It must have a high frequency bypass capacitor of approximately 0.1 μ F connected between V_{CC} and V_{SS} using leads and traces that are as short as possible. As with all high speed CMOS ICs, careful routing of power, ground, and signals reduce circuit noise.

Low Average Active Power

CMOS technology provides CY14B256K which enables drawing less current when it is cycled at times longer than 50 ns. Figure 2 shows the relationship between I_{CC} and READ and/or WRITE cycle time. Worst case current consumption is shown for commercial temperature range, $V_{CC}=3.6\mathrm{V}$, and chip enable at maximum frequency. Only standby current is drawn when the chip is disabled. The overall average current drawn by the CY14B256K depends on the following items:

- 1. 1The duty cycle of chip enable
- 2. The overall cycle rate for accesses
- 3. The ratio of READs to WRITEs
- 4. The operating temperature
- 5. The V_{CC} level
- 6. IO loading

Figure 2. Current versus Cycle Time



Real Time Clock Operation

nvTIME Operation

The CY14B256K consists of internal registers that contain clock, alarm, watchdog, interrupt, and control functions. Internal double buffering of the clock and the clock/timer information registers prevents accessing transitional internal clock data during a read or write operation. Double buffering also circumvents disrupting normal timing counts or clock accuracy of the internal clock while accessing clock data. Clock and Alarm registers store data in BCD format.

Notes

- 1. The six consecutive address locations are in the order listed. WE is HIGH during all six cycles to enable a nonvolatile cycle.
- 2. While there are 15 address lines on the CY14B256K, only the lower 14 lines are used to control software modes.
- 3. IO state depends on the state of \overline{OE} . The IO table shown is based on \overline{OE} Low.



Clock Operations

The Clock registers maintain time up to 9,999 years in one second increments. The user sets the time to any calendar time and the clock automatically keeps track of days of the week, month, leap years, and century transitions. There are eight registers dedicated to the clock functions that are used to set time with a write cycle and to read time during a read cycle. These registers contain the time of day in BCD format. Bits defined as '0' are currently not used and are reserved for future use by Cypress.

Reading the Clock

The double buffered RTC register structure reduces the chance of reading incorrect data from the clock. But stop internal updates to the CY14B256K Clock registers before reading clock data to prevent the reading of data in transition. Stopping the internal register updates does not affect clock accuracy. The update process is stopped by writing a '1' to the read bit R (in the Flags register at 0x7FF0) and does not restart until a '0' is written to the read bit. The RTC registers is then read while the internal clock continues to run. Within 20 ms after a '0' is written to the read bit, all CY14B256K registers are simultaneously updated.

Setting the Clock

Setting the write bit W (in the Flags register at 0x7FF0) to a '1' stops updates to the CY14B256K registers. The correct day, date, and time is then written into the registers in 24 hour BCD format. The time written is referred to as the Base Time. This value is stored in nonvolatile registers and used in calculation of the current time. Resetting the write bit to '0' transfers those values to the actual clock counters after which the clock resumes normal operation.

Backup Power

The RTC in the CY14B256K is used for permanently powered operation. Either the V_{RTCcap} or V_{RTCbat} pin is connected depending on whether a capacitor or battery is chosen for the application. When primary power, V_{CC} , fails and drops below V_{SWITCH} , the device switches to the backup power supply.

The clock oscillator uses very little current to maximize the backup time available from the backup source. Regardless of clock operation with the primary source removed, the data stored in nvSRAM is secure, as it is stored in the nonvolatile elements when power was lost.

During backup operation, the CY14B256K consumes a maximum of 300 nA at 2V. Capacitor or battery values are chosen according to the application. Backup time values, based on maximum current specifications, are shown in Table 2 on page 6. Nominal times are approximately three times longer.

Table 2. RTC Backup Time

Capacitor Value	Backup Time
0.1F	72 hours
0.47F	14 days
1.0F	30 days

Using a capacitor has the advantage of recharging the backup source each time the system is powered up. If a battery is used, use a 3V lithium and the CY14B256K only sources current from

the battery when the primary power is removed. The battery does not, however, recharge at any time by the CY14B256K. The battery capacity is chosen for total anticipated cumulative down time required over the life of the system.

Stopping and Starting the Oscillator

The OSCEN bit in Calibration register at 0x7FF8 controls the starting and stopping of the oscillator. This bit is nonvolatile and shipped to customers in the enabled (set to '0') state. To preserve battery life while system is in storage, OSCEN is set to a '1'. This turns off the oscillator circuit, extending the battery life. If the OSCEN bit goes from disabled to enabled, it takes approximately five seconds (10 seconds max) for the oscillator to start.

The CY14B256K has the ability to detect oscillator failure. This is recorded in the OSCF (Oscillator Failed bit) of the Flags register at address 0x7FF0. When the device is powered on (V_{CC} goes above V_{SWITCH}), the OSCEN bit is checked for enabled status. If the OSCEN bit is enabled and the oscillator is not active, the OSCF bit is set. The user must check for this condition and then write a '0' to clear the flag. In addition to setting the OSCF flag bit, the Time registers are reset to the Base Time (for more information, see "Setting the Clock" on page 6): the value last written to the time keeping registers. The Control or Calibration register and the OSCEN bit are not affected by the oscillator failed condition.

If the voltage on the backup supply (either V_{RTCcap} or V_{RTCbat}) falls below its minimum level, the oscillator may fail, leading to the oscillator failed condition that is detected when system power is restored.

The value of OSCF is reset to '0' when the time registers are written for the first time. This initializes the state of this bit that is set when the system is first powered on.

Calibrating the Clock

The RTC is driven by a quartz controlled oscillator with a nominal frequency of 32.768 kHz. Clock accuracy depends on the quality of the crystal usually specified to 35 ppm limits at 25°C. This error equates to +1.53 minutes per month. The CY14B256K employs a calibration circuit that improves the accuracy to +1/–2 ppm at 25°C. The calibration circuit adds or subtracts counts from the oscillator divider circuit.

The number of pulses that are suppressed (subtracted, negative calibration) or split (added, positive calibration) depends upon the value loaded into the five calibration bits found in Calibration register at 0x7FF8. Adding counts speeds the clock up and subtracting counts slows the clock down. The calibration bits occupy the five lower order bits in the Control register 8. These bits are set to represent any value between '0' and 31 in binary form. Bit D5 is a sign bit, where a '1' indicates positive calibration and a '0' indicates negative calibration. Calibration occurs within a 64 minute cycle. The first 62 minutes in the cycle may, once per minute, have one second either shortened by 128 or lengthened by 256 oscillator cycles.

If a binary '1' is loaded into the register, only the first two minutes of the 64 minute cycle is modified. If a binary 6 is loaded, the first 12 are affected, and so on. Therefore, each calibration step has the effect of adding 512 or subtracting 256 oscillator cycles for every 125, 829,120 actual oscillator cycles, that is, 4.068 or -2.034 ppm of adjustment per calibration step in the Calibration register.

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To determine how to set the calibration, one may set the CAL bit in the Flags register at 0x7FF0 to '1' that causes the INT pin to toggle at a nominal 512 Hz. Any deviation measured from the 512 Hz indicates the degree and direction of the required correction. For example, a reading of 512.010124 Hz indicates a +20 ppm error, requiring to load a -10 (001010) into the Calibration register. Note that setting or changing the Calibration register does not affect the frequency test output frequency.

Alarm

The alarm function compares user programmed values to the corresponding time-of-day values. When a match occurs, the alarm event occurs. The alarm drives an internal flag, AF, and may drive the INT pin if desired.

There are four alarm match fields. They are date, hours, minutes, and seconds. Each of these fields also has a Match bit that is used to determine if the field is used in the alarm match logic. Setting the Match bit to '0' indicates that the corresponding field is used in the match process.

Depending on the Match bits, the alarm occurs as specifically as one particular second on one day of the month or as frequently as once per second continuously. The MSb of each alarm register is a Match bit. Selecting none of the Match bits (all 1s) indicates that no match is required. The alarm occurs every second. Setting the match select bit for seconds to '0' causes the logic to match the seconds alarm value to the current time of the day. Since a match occurs for only one value per minute, the alarm occurs once per minute. Likewise, setting the seconds and minutes, Match bits cause an exact match of these values. Thus, an alarm occurs once per hour. Setting seconds, minutes, and hours causes a match once per day. Lastly, selecting all match values causes an exact time and date match. Selecting other bit combinations does not produce meaningful results. However, the alarm circuit must follow the functions described.

There are two ways a user can detect an alarm event. They are by reading the AF flag or monitoring the INT pin. The AF flag in the Flags register at 0x7FF0 indicates that a date and time match has occurred. The AF bit is set to '1' when a match occurs. Reading the Flags or Control register clears the Alarm flag bit (and all others). A hardware interrupt pin is also used to detect an alarm event.

Watchdog Timer

The Watchdog Timer is a free running down counter that uses the 32 Hz clock (31.25 ms) derived from the crystal oscillator. The oscillator is running for the watchdog to function. It begins counting down from the value loaded in the Watchdog Timer register.

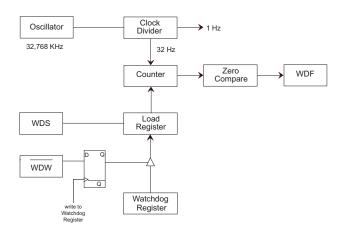
The counter consists of a loadable register and a free running counter. On power up, the watchdog time out value in register 0x7FF7 is loaded into the Counter Load register. Counting begins on power up and restarts from the loadable value any time the Watchdog Strobe (WDS) bit is set to '1'. The counter is compared to the terminal value of '0'. If the counter reaches this value, it causes an internal flag and an optional interrupt output. You can prevent the time out interrupt by setting WDS bit to '1' prior to the counter reaching '0'. This causes the counter to reload with the watchdog time out value and to be restarted. As

long as the user sets the WDS bit prior to the counter reaching the terminal value, the interrupt and flag never occur.

New time out values are written by setting the watchdog write bit to '0'. When the WDW is '0' (from the previous operation), new writes to the watchdog time out value bits D5-D0 enable to modify the time out value. When WDW is a '1', writes to bits D5-D0 are ignored. The WDW function enables a user to set the WDS bit without concern that the watchdog timer value is modified. A logical diagram of the watchdog timer is shown in Figure 3. Note that setting the watchdog time out value to '0' is otherwise meaningless and therefore disables the watchdog function.

The output of the watchdog timer is the flag bit WDF that is set if the watchdog is allowed to time out. The flag is set upon a watchdog time out and cleared when the user reads the Flags or Control registers. If the watchdog time out occurs, the user also enables an optional interrupt source to drive the INT pin.

Figure 3. Watchdog Timer Block Diagram



Power Monitor

The CY14B256K provides a power management scheme with power fail interrupt capability. It also controls the internal switch to backup power for the clock and protects the memory from low V_{CC} access. The power monitor is based on an internal band gap reference circuit that compares the V_{CC} voltage to various thresholds.

As described in the "AutoStore Operation" on page 3, when V_{SWITCH} is reached as V_{CC} decays from power loss, a data store operation is initiated from SRAM to the nonvolatile elements, securing the last SRAM data state. Power is also switched from VCC to the backup supply (battery or capacitor) to operate the RTC oscillator.

When operating from the backup source, no data is read or written and the clock functions are not available to the user. The clock continues to operate in the background. Updated clock data is available to the user after VCC is restored to the device and t_{HRECALL} delay (see "AutoStore or Power Up RECALL" on page 17).

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Interrupts

The CY14B256K provides three potential interrupt sources. They include the watchdog timer, the power monitor, and the clock or calendar alarm. Each is individually enabled and assigned to drive the INT pin. In addition, each has an associated flag bit that the host processor uses to determine the cause of the interrupt. Some of the sources have additional control bits that determine functional behavior. In addition, the pin driver has three bits that specify its behavior when an interrupt occurs.

Each of the three interrupts have a source and an enable. Both the source and the enable are active (true high) to generate an interrupt output. Only one source is necessary to drive the pin. The user identifies the source by reading the Flags or Control registers that contains the flags associated with each source. All flags are cleared to '0' when the register is read. The flags are cleared only after a complete read cycle (WE high). The power monitor has two programmable settings that is explained in the "Power Monitor" on page 7.

When an interrupt source is active, the pin driver determines the behavior of the output. It has two programmable settings as shown in the following sections. Pin driver control bits are located in the Interrupts register.

According to the programming selections, the pin is driven in the backup mode for an alarm interrupt. In addition, the pin is an active LOW (open drain) or an active HIGH (push pull) driver. If programmed for operation during backup mode, it is only active LOW. Lastly, the pin provides a one shot function so that the active condition is a pulse or a level condition. In one shot mode, the pulse width is internally fixed at approximately 200 ms. This mode is intended to reset a host microcontroller. In Level mode, the pin goes to its active polarity until the user reads the Flags or Control registers. This mode is used as an interrupt to a host microcontroller. The Interrupt register is initialized to 00h. The control bits are summarized as follows:

Watchdog Interrupt Enable - WIE. When set to '1', the watchdog timer drives the INT pin and an internal flag when a watchdog time out occurs. When WIE is set to '0', the watchdog timer affects only the internal flag.

Alarm Interrupt Enable - AIE. When set to '1', the alarm match drives the INT pin and an internal flag. When set to '0', the alarm match only affects to internal flag.

Power Fail Interrupt Enable - PFE. When set to '1', the power fail monitor drives the pin and an internal flag. When set to '0', the power fail monitor affects only the internal flag.

High/Low - H/L. When set to a '1', the INT pin is active HIGH and the driver mode is push pull. The INT pin drives high only when V_{CC} is greater than V_{SWITCH} . When set to a '0', the INT pin is active LOW and the drive mode is open drain. Active LOW (open drain) is operational even in battery backup mode.

Pulse/Level - P/L. When set to a '1' and an interrupt occurs, the INT pin is driven for approximately 200 ms. When P/L is set to a '0', the INT pin is driven high or low (determined by H/L) until the Flags or Control register is read.

When an enabled interrupt source activates the INT pin, an external host reads the Flags or Control registers to determine the cause. Remember that all flags are cleared when the register is read. If the INT pin is programmed for Level mode, then the condition clears and the INT pin returns to its inactive state. If the pin is programmed for Pulse mode, then reading the flag also clears the flag and the pin. The pulse does not complete its specified duration if the Flags or Control register is read. If the INT pin is used as a host reset, then the Flags or Control register is not read during a reset.

During a power on reset with no battery, the Interrupt register is automatically loaded with the value 24h. This causes power fail interrupt to be enabled with an active low pulse.

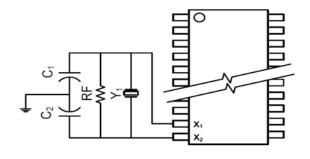
Flags Register - The Flags register has three flag bits: WDF, AF, and PF. These flag bits are initialized to 00h. These flags are set by the watchdog time out, alarm match, or power fail monitor respectively. The processor either polls this register or enable to inform the interrupts when a flag is set. The flags are automatically reset when the register is read.

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WDF Watchdog Timer WIE WDF - Watchdog Timer Flag WIE - Watchdog Interrupt $V_{\!CC}$ P/L Enable PF PF - Power Fail Flag Power Pin PFE - Power Fail Enable Monitor INT PFE Driver AF - Alarm Flag VINT AIE - Alarm Interrupt Enable H/L P/L - Pulse Level V_{SS} H/L - High/Low AF Clock Alarm AIE

Figure 4. RTC Recommended Component Configuration



Recommended Values

Y1 = 32.768 KHz

RF = 10M Ohm

 $C_1 = 0$

 $C_2^1 = 56 \text{ pF}$



Table 3. RTC Register Map

Dogiotor				BCD	Format Da	ta			Eunotion/Dongo
Register	D7	D6	D5	D4	D3	D2	D1	D0	- Function/Range
0x7FFF		10s	Years			Y	ears		Years: 00-99
0x7FFE	0	0	0	10s Months		М	onths		Months: 01–12
0x7FFD	0	0	10s Day	of Month		Day C	Of Month		Day of Month: 01-31
0x7FFC	0	0	0	0	0		Day of w	eek	Day of week: 01–07
0x7FFB	0	0	10s F	lours		Н	ours		Hours: 00-23
0x7FFA	0	1	0s Minute	:S		Mi	nutes		Minutes: 00-59
0x7FF9		1	0s Second	ds		Se	conds		Seconds: 00-59
0x7FF8	OSCEN	0	Cal Sign	Calibra			on		Calibration Values [4]
0x7FF7	WDS	WDW			V	VDT			Watchdog ^[4]
0x7FF6	WIE	AIE	PFE	0	H/L	P/L	0	0	Interrupts [4]
0x7FF5	M	0	10s Alaı	m Date		Alar	m Day		Alarm, Day of Month: 01-31
0x7FF4	M	0	10s Aları	m Hours		Alarr	n Hours		Alarm, Hours: 00-23
0x7FF3	M	10 /	Alarm Min	utes		Alarm	Minutes		Alarm, Minutes: 00-59
0x7FF2	M	10 /	Alarm Min	utes		Alarm,	Seconds		Alarm, Seconds: 00-59
0x7FF1		10s C	enturies	turies			nturies		Centuries: 00–99
0x7FF0	WDF	AF	PF	OSCF	0	CAL	W	R	Flags ^[4]

Table 4. Register Map Detail

	Time Keeping - Years										
0x7FFF	D7	D6	D5	D4	D3	D2	D1	D0			
		10s	Years			Ye	ears				
		Contains the lower two BCD digits of the year. Lower nibble contains the value for years; upper nibble contains the value for 10s of years. Each nibble operates from 0 to 9. The range for the register is 0–99.									
				Time Keepin	g - Months						
	D7	D6	D5	D4	D3	D2	D1	D0			
0x7FFE	0	0	0	10s Month		Мс	onths				
	Contains the BCD digits of the month. Lower nibble contains the lower digit and operates from 0 to 9; upper nibble (one bit) contains the upper digit and operates from 0 to 1. The range for the register is 1–12.										
	Time Keeping - Date										
	D7	D6	D5	D4	D3	D2	D1	D0			
0x7FFD	0	0	10s Day	of Month		Day o	Day of Month				
	upper nibble	Contains the BCD digits for the date of the month. Lower nibble contains the lower digit and operates from 0 to 9; upper nibble contains the upper digit and operates from 0 to 3. The range for the register is 1–31. Leap years are automatically adjusted for.									
				Time Keep	ing - Day						
	D7	D6	D5	D4	D3	D2	D1	D0			
0x7FFC	0	0	0	0	0		Day of Weel	(
			ue that correlate e user must ass								

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Note
4. Is a binary value, not a BCD value.



Table 4. Register Map Detail (continued)

				Time Keepii	ng - Hours						
	D7	D6	D5	D4	D3	D2	D1	D0			
0x7FFB	12/24 0 10s Hours Hours										
	Contains the BCD value of hours in 24 hour format. Lower nibble contains the lower digit and operates from 0 to 9; upper nibble (two bits) contains the upper digit and operates from 0 to 2. The range for the register is 0–23.										
	Time Keeping - Minutes										
	D7	D6	D5	D4	D3	D2	D1	D0			
0x7FFA	0		10s Minutes			Mir	nutes				
			minutes. Lower digit and opera					upper nibble			
				Time Keeping	g - Seconds						
	D7	D6	D5	D4	D3	D2	D1	D0			
0x7FF9	0		10s Seconds			Sec	conds	ı			
	Contains the BCD value of seconds. Lower nibble contains the lower digit and operates from 0 to 9; upper nibble contains the upper digit and operates from 0 to 5. The range for the register is 0–59.										
				Calibration	n/Control						
0X7FF8	D7	D6	D5	D4	D3	D2	D1	D0			
UXTITO	OSCEN	0	Calibration Sign			Calibration		1			
OSCEN			to '1', the oscill power during sto					g the oscillator			
Calibration Sign	Determines i	f the calibration	n adjustment is	applied as an a	ddition to or a	s a subtraction	n from the tim	e base.			
Calibration	These five bi	its control the c	alibration of the	clock.							
				WatchDo	g Timer						
0x7FF7	D7	D6	D5	D4	D3	D2	D1	D0			
	WDS	WDW			WE	T					
WDS			nis bit to '1' relo								
WDW	written. This allows bits 5-	enables the us -0 to be written	etting this bit to ' er to strobe the on the next writ ite cycle is com	watchdog with te to the Watcho	out disturbing log register. T	the time out v he new value i	alue. Setting to some some setting to the setting t	this bit to '0' ne next internal			
WDT	a multiplier o	of the 32 Hz countries two	on. The watchdount (31.25 ms). It is seconds (setting the WDW bit is	The minimum rang of 3 Fh). Set	ange or time of ting the Watch	out value is 31 idog Timer reg	.25 ms (a sett	ting of '1') and			



Table 4. Register Map Detail (continued)

				Interrupt Sta	tus/Control					
0x7FF6	D7	D6	D5	D4	D3	D2	D1	D0		
	WIE	AIE	PFIE	0	H/L	P/L	0	0		
WIE	Watchdog Interrupt Enable. When set to '1' and a watchdog time out occurs, the watchdog timer drives the INT pin and the WDF flag. When set to '0', the watchdog time out affects only the WDF flag.									
AIE	Alarm Interrupt Enable. When set to '1', the alarm match drives the INT pin and the AF flag. When set to '0', the alarm match only affects the AF flag.									
PFIE	Power Fail Enable. When set to '1', the alarm match drives the INT pin and the PF flag. When set to '0', the power fail monitor affects only the PF flag.									
H/L	High/Low. W	hen set to a '1',	the INT pin is d	riven active HIG	SH. When set	to '0', the INT p	oin is open drai	n, active LOW.		
P/L	mately 200 n	Pulse/Level. When set to a '1', the INT pin is driven active (determined by H/L) by an interrupt source for approximately 200 ms. When set to a '0', the INT pin is driven to an active level (as set by H/L) until the Flags or Control register is read.								
				Alarm	- Day					
0x7FF5	D7	D6	D5	D4	D3	D2	D1	D0		
UXTEFS	M	0	10s Ala	rm Date		Alarn	n Date			
	Contains the	alarm value fo	r the date of the	e month and the	mask bit to s	select or desele	ect the date va	alue.		
M		ng this bit to '0' to ignore the c	causes the date	e value to be us	sed in the alar	m match. Setti	ing this bit to '	1' causes the		
				Alarm -	Hours					
0x7FF4	D7	D6	D5	D4	D3	D2	D1	D0		
UX/FF4	M 0 10s Alarm Hours Alarm Hours									
	Contains the	alarm value fo	r the hours and	the mask bit to	select or des	elect the hours	s value.			
	Match. Setting this bit to '0' causes the hours value to be used in the alarm match. Setting this bit to '1' causes the match circuit to ignore the hours value.									
M				ırs value to be ι	ised in the ala	arm match. Set	ting this bit to	'1' causes the		
M				rs value to be u		arm match. Set	ting this bit to	'1' causes the		
						arm match. Set	ting this bit to	'1' causes the		
M 0x7FF3	match circuit	to ignore the h	nours value.	Alarm - N	/linutes	D2				
	match circuit D7 M	to ignore the h	nours value.	Alarm - N D4 n Minutes	Ainutes D3	D2 Alarm	D1 Minutes			
	D7 M Contains the Match. Settin	D6 0 alarm value fo	D5 10s Alarn	Alarm - N D4 n Minutes nd the mask bit	D3 to select or d	D2 Alarm leselect the mil	D1 Minutes nutes value.	D0		
0x7FF3	D7 M Contains the Match. Settin	D6 0 alarm value fo	D5 10s Alarn r the minutes a causes the min	Alarm - N D4 n Minutes nd the mask bit	D3 to select or de used in the	D2 Alarm leselect the mil	D1 Minutes nutes value.	D0		
0x7FF3	D7 M Contains the Match. Settin	D6 0 alarm value fo	D5 10s Alarn r the minutes a causes the min	Alarm - M D4 In Minutes Ind the mask bit outes value to be	D3 to select or de used in the	D2 Alarm leselect the mil	D1 Minutes nutes value.	D0		
0x7FF3	D7 M Contains the Match. Settin	D6 0 alarm value for out to ignore the	D5 10s Alarn or the minutes a causes the min the minutes valu	Alarm - M D4 n Minutes nd the mask bit sutes value to be le. Alarm - S	D3 to select or de used in the econds	D2 Alarm leselect the miralarm match. S	D1 Minutes nutes value. Setting this bit	D0 to '1' causes		
0x7FF3	match circuit D7 M Contains the Match. Settin the match cir D7 M	D6 0 alarm value for go this bit to '0' cuit to ignore to D6 0	D5 10s Alarn or the minutes a causes the min the minutes valu	Alarm - M D4 In Minutes Ind the mask bit lutes value to be lee. Alarm - S D4 In Seconds	to select or de used in the econds	D2 Alarm leselect the milliple alarm match. S D2 Alarm S	D1 Minutes nutes value. Setting this bit D1 Seconds	D0 to '1' causes		
0x7FF3	match circuit D7 M Contains the Match. Settin the match cir D7 M Contains the Match. Settin	D6 0 alarm value for gethis bit to '0' cuit to ignore the D6 0 alarm value for gethis bit to '0' gethis bit to '0' gethis bit to '0' gethis bit to '0'	D5 10s Alarm r the minutes a causes the min he minutes valu D5 10s Alarm	Alarm - M D4 In Minutes Ind the mask bit outes value to be le. Alarm - S D4 In Seconds Ind the mask bit onds value to be leaded.	to select or de used in the econds D3 to select or de used in the econds	Alarm leselect the min alarm match. S D2 Alarm S deselect the se	D1 Minutes nutes value. Setting this bit D1 Seconds	D0 to '1' causes D0		
0x7FF3 M 0x7FF2	match circuit D7 M Contains the Match. Settin the match cir D7 M Contains the Match. Settin	D6 0 alarm value for gethis bit to '0' cuit to ignore the D6 0 alarm value for gethis bit to '0' gethis bit to '0' gethis bit to '0' gethis bit to '0'	D5 10s Alarm r the minutes a causes the min the minutes value D5 10s Alarm r the seconds a causes the seconds a	Alarm - M D4 In Minutes Ind the mask bit outes value to be le. Alarm - S D4 In Seconds Ind the mask bit onds value to be leaded.	to select or de used in the econds D3 to select or de used in the econds D3 to select or de used in the econds	Alarm leselect the min alarm match. S D2 Alarm S deselect the se	D1 Minutes nutes value. Setting this bit D1 Seconds	D0 to '1' causes D0		
0x7FF3 M 0x7FF2	match circuit D7 M Contains the Match. Settin the match cir D7 M Contains the Match. Settin	D6 0 alarm value for gethis bit to '0' cuit to ignore the D6 0 alarm value for gethis bit to '0' gethis bit to '0' gethis bit to '0' gethis bit to '0'	D5 10s Alarm r the minutes a causes the min the minutes value D5 10s Alarm r the seconds a causes the seconds a	Alarm - M D4 In Minutes Ind the mask bit Inutes value to be Ide. Alarm - S D4 In Seconds Ind the mask bit Indian the mask bit Indian seconds Indian the mask bit Indian seconds Indian se	to select or de used in the econds D3 to select or de used in the econds D3 to select or de used in the econds	Alarm leselect the min alarm match. S D2 Alarm S deselect the se	D1 Minutes nutes value. Setting this bit D1 Seconds	D0 to '1' causes D0		



Table 4. Register Map Detail (continued)

		Flags									
0x7FF0	D7	D6	D5	D4	D3	D2	D1	D0			
	WDF	CAL	W	R							
WDF	Watchdog Timer Flag. This read only bit is set to '1' when the watchdog timer is allowed to reach '0' without being reset by the user. It is cleared to '0' when the Flags or Control register is read.										
AF		Alarm Flag. This read only bit is set to '1' when the time and date match the values stored in the alarm registers with the match bits = 0. It is cleared when the Flags or Control register is read.									
PF	Power Fail Flag. This read only bit is set to '1' when power falls below the power fail threshold V _{SWITCH} . It is cleared to '0' when the Flags or Control register is read.										
OSCF	Oscillator Fail Flag. Set to '1' on power up only if the oscillator is not running in the first 5 ms of power on operation. This indicates that time counts are no longer valid. The user must reset this bit to '0' to clear this condition. The chip does not clear this flag. This bit survives power cycles.										
CAL		Calibration Mode. When set to '1', a 512 Hz square wave is output on the INT pin. When set to '0', the INT pin resumes normal operation. This bit defaults to '0' (disabled) on power up.									
W	updated valu	Write Time. Setting the W bit to '1' freezes updates of the time keeping registers. The user then writes them with updated values. Setting the W bit to '0' transfers the contents of the time registers to the time keeping counters. The W bit enables writes to RTC, Alarm, Calibration, Interrupt, and Flag registers. [5]									
R	register. The	Read Time. Setting the R bit to '1' copies a static image of the time keeping registers and places them in a holding register. The user then reads them without concerns over changing values causing system errors. The R bit going from '0' to '1' causes the time keeping capture, so the bit is returned to '0' prior to reading again.									

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Note
5. W bit is set to write to any of the RTC registers except the Flag register (0X1FFF1 to 0X1FFFF).



Maximum Ratings

Exceeding maximum ratings may impair the useful life of the

device. These user guidelines are not tested.
Storage Temperature65°C to +150°C
Ambient Temperature with Power Applied –55°C to +125°C
Supply Voltage on V _{CC} Relative to GND0.5V to 4.1V
Voltage Applied to Outputs in High Z State0.5V to V _{CC} + 0.5V
Input Voltage0.5V to Vcc+0.5V
Transient Voltage (<20 ns) on Any Pin to Ground Potential–2.0V to V _{CC} + 2.0V

Package Power Dissipation Capability (T _A = 25°C)	1.0W
Surface Mount Pb Soldering Temperature (3 Seconds)	+260°C
Output Short Circuit Current [6]	15 mA
Static Discharge Voltage(MIL-STD-883, Method 3015)	> 2001V
Latch Up Current	> 200 mA
O (' D	

Operating Range

Range	Ambient Temperature	V _{CC}
Commercial	0°C to +70°C	2.7V to 3.6V
Industrial	–40°C to +85°C	2.7V to 3.6V

DC Electrical Characteristics

Over the Operating Range (VCC = 2.7V to 3.6V) $^{[7, 8, 9]}$

Parameter	Description	Test Conditions	Min	Max	Unit	
I _{CC1}	Average V _{CC} Current	t_{RC} = 35 ns t_{RC} = 45 ns	Commercial		65 55 50	mA mA mA
		Dependent on output loading and cycle rate. Values obtained without output loads. I _{OUT} = 0 mA.	Industrial		55 (t _{RC} = 45 ns)	mA mA mA
I _{CC2}	Average V _{CC} Current during STORE	All Inputs Do Not Care, V _{CC} = Max Average current for duration t _{STORE}			3	mA
I _{CC3}	Average V_{CC} Current at t_{AVAV} = 200 ns, 3V, 25°C Typical	WE > (V _{CC} - 0.2). All other inputs cycling. Dependent on output loading and cycle rate. Values obtained without output loads.			10	mA
I _{CC4}	Average V _{CAP} Current during AutoStore Cycle	All Inputs Do Not Care, V _{CC} = Max Average current for duration t _{STORE}			3	mA
I _{SB}	V _{CC} Standby Current	$\overline{\rm WE}$ > (V _{CC} - 0.2). All others V _{IN} < 0.2V or > (V _C Standby current level after nonvolatile cycle is conjugate and the state of the state	_{CC} – 0.2V). omplete.		3	mA
I _{IX}	Input Leakage Current	$V_{CC} = Max, V_{SS} \le V_{IN} \le V_{CC}$		-1	+1	μА
l _{OZ}	Off State Output Leakage Current	$V_{CC} = Max, V_{SS} \le V_{IN} \le V_{CC}, \overline{CE} \text{ or } \overline{OE} > V_{IH}$		-1	+1	μА
V _{IH}	Input HIGH Voltage			2.0	V _{CC} + 0.3	V
V _{IL}	Input LOW Voltage			V _{SS} - 0.5	0.8	V
V _{OH}	Output HIGH Voltage	$I_{OUT} = -2 \text{ mA}$		2.4		V
V _{OL}	Output LOW Voltage	I _{OUT} = 4 mA			0.4	V
V _{CAP}	Storage Capacitor	Between V _{CAP} pin and V _{SS} , 5V Rated		17	120	μF

- 6. Outputs shorted for no more than one second. No more than one output shorted at a time.
- Supplied conditions for the Active Current shown on the front page of the data sheet are average values at 25°C (room temperature) and VCC = 3V. Not 100% tested.
 The HSB pin has IOUT = -10 μA for VOH of 2.4V, this parameter is characterized but not tested.
- 9. The INT pin is open drain and does not source or sink current when Interrupt register bit D3 is low.

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CapacitanceThese parameters are guaranteed but not tested.

Parameter	Description	Test Conditions	Max	Unit
C _{IN}	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	7	pF
C _{OUT}	Output Capacitance	$V_{CC} = 0$ to 3.0 V	7	pF

Thermal Resistance

These parameters are guaranteed but not tested.

Parameter	Description	Test Conditions	48-SSOP	Unit
Θ_{JA}		Test conditions follow standard test methods and procedures for measuring thermal impedance, in	TBD	°C/W
$\Theta_{\sf JC}$	Thermal Resistance (Junction to Case)	accordance with EIA / JESD51.	TBD	°C/W

AC Test Loads



AC Test Conditions

Input Pulse Levels) V to 3 V
Input Rise and Fall Times (10% - 90%)	<u><</u> 5 ns
Input and Output Timing Reference Levels	1.5 V

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AC Switching Characteristics

Parar	neter		25 ns	s Part	35 ns Part		45 ns Part		
Cypress Parameter	Alt. Parameter	Description	Min	Max	Min	Max	Min	Max	Unit
SRAM Read	Cycle								
t _{ACE}	t _{ACS}	Chip Enable Access Time		25		35		45	ns
t _{RC} [11]	t _{RC}	Read Cycle Time	25		35		45		ns
t _{AA} ^[12]	t _{AA}	Address Access Time		25		35		45	ns
t _{DOE}	t _{OE}	Output Enable to Data Valid		12		15		20	ns
t _{OHA} [12]	t _{OH}	Output Hold After Address Change	3		3		3		ns
t _{LZCE} [13]	t_{LZ}	Chip Enable to Output Active	3		3		3		ns
t _{HZCE} [13]	t _{HZ}	Chip Disable to Output Inactive		10		13		15	ns
t _{LZOE} [13]	t _{OLZ}	Output Enable to Output Active	0		0		0		ns
t _{HZOE} [13]	t _{OHZ}	Output Disable to Output Inactive		10		13		15	ns
t _{PU} ^[10]	t _{PA}	Chip Enable to Power Active	0		0		0		ns
t _{PD} ^[10]	t _{PS}	Chip Disable to Power Standby		25		35		45	ns
SRAM Write	Cycle								
t _{WC}	t _{WC}	Write Cycle Time	25		35		45		ns
t _{PWE}	t _{WP}	Write Pulse Width	20		25		30		ns
t _{SCE}	t _{CW}	Chip Enable To End of Write	20		25		30		ns
t _{SD}	t _{DW}	Data Setup to End of Write	10		12		15		ns
t _{HD}	t _{DH}	Data Hold After End of Write	0		0		0		ns
t _{AW}	t _{AW}	Address Setup to End of Write	20		25		30		ns
t _{SA}	t _{AS}	Address Setup to Start of Write	0		0		0		ns
t _{HA}	t _{WR}	Address Hold After End of Write	0		0		0		ns
t _{HZWE} [13, 14]	t_{WZ}	Write Enable to Output Disable		10		13		15	ns
t _{LZWE} [13]	t _{OW}	Output Active After End of Write	3		3		3		ns

Notes

^{10.} These parameters are guaranteed but not tested.11. WE is HIGH during SRAM Read Cycles.12. Device is continuously selected with CE and OE both Low.

^{13.} Measured ±200 mV from steady state output voltage.14. If WE is Low when CE goes Low, the outputs remain in the High Impedance State.



AutoStore or Power Up RECALL

Doromotor	Description	CY14E	Unit	
Parameter	Description	Min	Max	Onit
t _{HRECALL} [15]	Power Up RECALL Duration		20	ms
t _{STORE} [16, 17]	STORE Cycle Duration		12.5	ms
V _{SWITCH}	Low Voltage Trigger Level		2.65	V
t _{VCCRISE}	VCC Rise Time	150		μS

Software Controlled STORE/RECALL Cycles [18, 19]

Parameter	Description		25 ns Part		35 ns Part		45 ns Part	
Parameter			Max	Min	Max	Min	Max	Unit
t _{RC}	STORE/RECALL Initiation Cycle Time	25		35		45		ns
t _{AS}	Address Setup Time	0		0		0		ns
t _{CW}	Clock Pulse Width	20		25		30		ns
t _{GHAX}	Address Hold Time	1		1		1		ns
t _{RECALL}	RECALL Duration		100		100		100	μS
t _{SS} ^[20, 21]	Soft Sequence Processing Time		70		70		70	μS

Hardware STORE Cycle

Parameter	Description	CY14E	Unit	
	Description	Min	Max	Oilit
t _{DELAY} [22]	Time Allowed to Complete SRAM Cycle	1	70	μs
t _{HLHX}	Hardware STORE Pulse Width	15		ns

Notes

- 15. t_{HRECALL} starts from the time V_{CC} rises above V_{SWITCH}.

 16. If an SRAM Write does not taken place since the last nonvolatile cycle, no STORE takes place.

 17. Industrial Grade Devices require 15 ms Max

 18. The software sequence is clocked with CE controlled or OE controlled READs.

- 19. The six consecutive addresses are read in the order listed in the Table 1 on page 5. WE is HIGH during all six consecutive cycles.
- 20. This is the amount of time it takes to take action on a soft sequence command. Vcc power must remain HIGH to effectively register command.
- 21. Commands such as STORE and RECALL lock out IO until operation is complete which further increases this time. See specific command.
- 22. Read and Write cycles in progress before HSB are given this amount of time to complete.

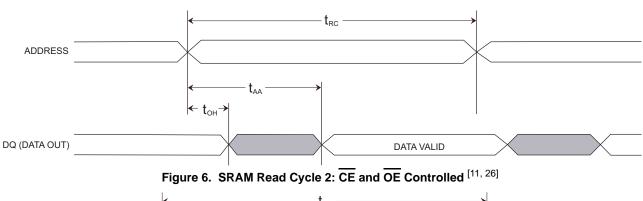


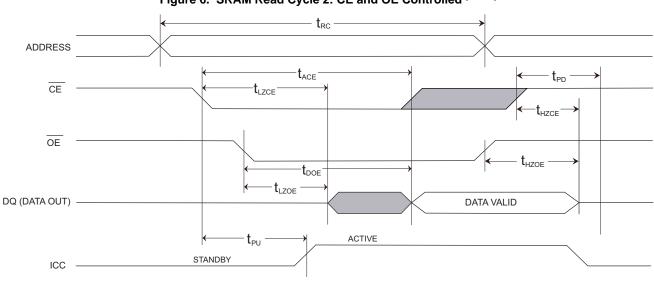
RTC Characteristics

Parameter	Description	Test Conditions		Min	Max	Unit
I _{BAK} [23]	RTC Backup Current		Commercial		300	nA
			Industrial		350	nA
V _{RTCbat} [24]	RTC Battery Pin Voltage		Commercial	1.8	3.3	V
			Industrial	1.8	3.3	V
V _{RTCcap} [25]	RTC Capacitor Pin Voltage		Commercial	1.2	2.7	V
			Industrial	1.2	2.7	V
		At Min Temperature from Power up or Enable	Commercial		10	sec
	Start	At 25°C Temperature from Power up or Enable	Commercial		5	sec
		At Min Temperature from Power up or Enable	Industrial		10	sec
		At 25°C Temperature from Power up or Enable	Industrial		5	sec

Switching Waveforms

Figure 5. SRAM Read Cycle 1: Address Controlled $^{[11,\ 12,\ 26]}$





- Notes
 23. From either V_{RTCcap} or V_{RTCbat}.
 24. Typical = 3.0V during normal operation.
 25. <u>Typical</u> = 2.4V during normal operation.
 26. HSB must remain HIGH during READ and WRITE cycles.



Switching Waveforms (continued)

Figure 7. SRAM Write Cycle 1: WE Controlled [26, 27]

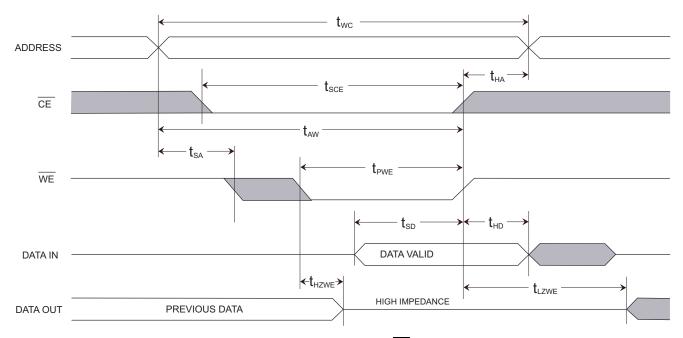
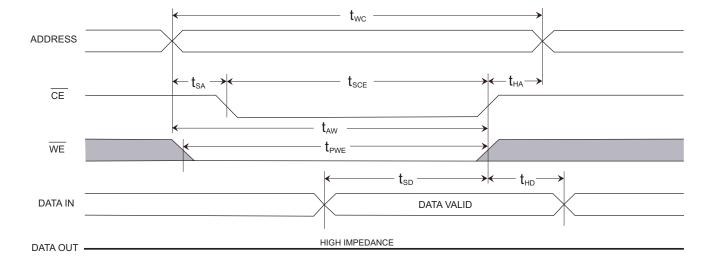


Figure 8. SRAM Write Cycle 2: $\overline{\text{CE}}$ Controlled



 $[\]label{eq:viscosity} \begin{array}{c} \textbf{Note} \\ \textbf{27.CE} \text{ or } \overline{\text{WE}} \text{ are greater than V}_{\text{IH}} \text{ during address transitions.} \end{array}$



Switching Waveforms (continued)

Figure 9. AutoStore/Power Up RECALL

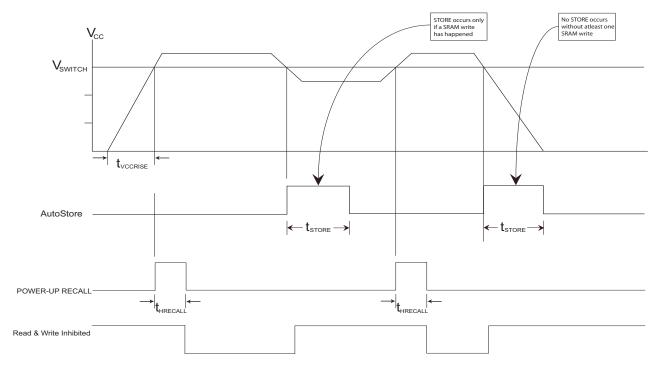
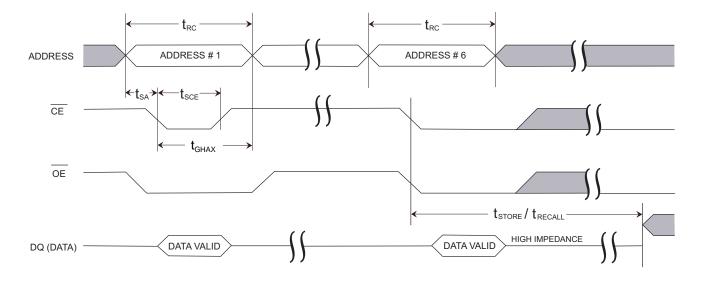


Figure 10. CE Controlled Software STORE/RECALL Cycle [19]





Switching Waveforms (continued)

Figure 11. OE Controlled Software STORE/RECALL Cycle [19]

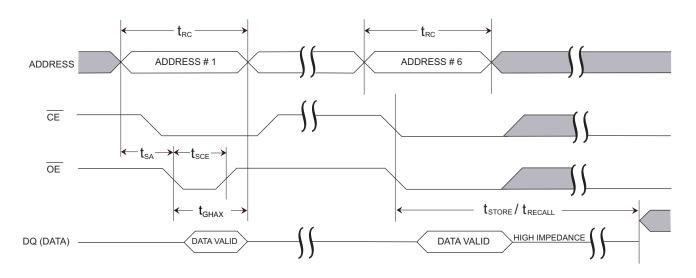


Figure 12. Soft Sequence Processing [20, 21]

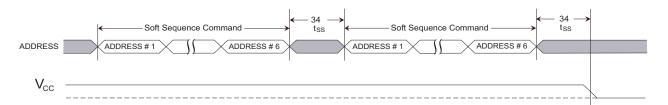
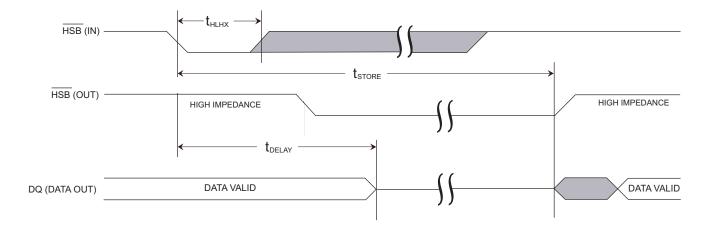
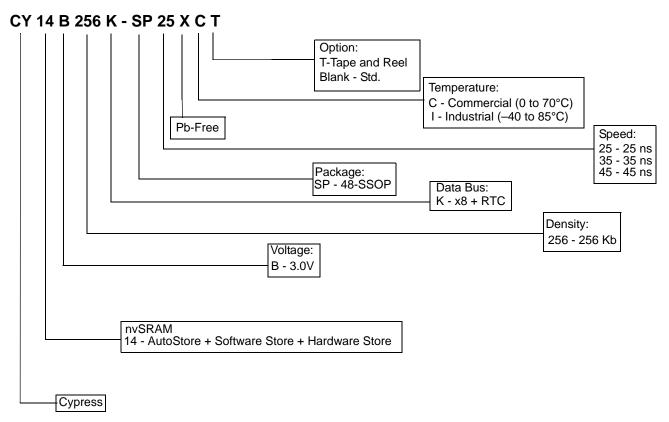


Figure 13. Hardware STORE Cycle





Part Numbering Nomenclature





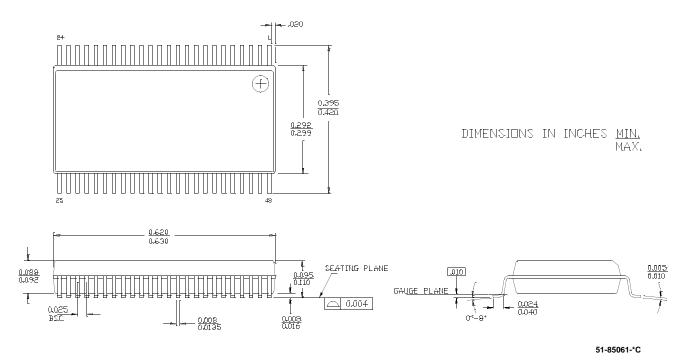
Ordering Information

All the below mentioned parts are Pb-free. Shaded areas contain advance information. Contact your local Cypress sales representative for availability of these parts.

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
25	CY14B256K-SP25XCT	51-85061	48-pin SSOP	Commercial
	CY14B256K-SP25XC	51-85061	48-pin SSOP	
25	CY14B256K-SP25XIT	51-85061	48-pin SSOP	Industrial
	CY14B256K-SP25XI	51-85061	48-pin SSOP	
35	CY14B256K-SP35XCT	51-85061	48-pin SSOP	Commercial
	CY14B256K-SP35XC	51-85061	48-pin SSOP	
35	CY14B256K-SP35XIT	51-85061	48-pin SSOP	Industrial
	CY14B256K-SP35XI	51-85061	48-pin SSOP	
45	CY14B256K-SP45XCT	51-85061	48-pin SSOP	Commercial
	CY14B256K-SP45XC	51-85061	48-pin SSOP	
45	CY14B256K-SP45XIT	51-85061	48-pin SSOP	Industrial
	CY14B256K-SP45XI	51-85061	48-pin SSOP	

Package Diagrams

Figure 14. 48-Pin Shrunk Small Outline Package(51-85061)



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Document History Page

Documen Documen	t Title: CY14 t Number: 0	B256K, 256 01-06431	Kbit (32K x	8) nvSRAM with Real Time Clock
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change
**	425138	See ECN	TUP	New data sheet
*A	437321	See ECN	TUP	Show data sheet on external Web
*B	471966	See ECN	TUP	Changed V _{IH(min)} from 2.2V to 2.0V Changed t _{RECALL} from 60 µs to 100 µs Changed Endurance from one million cycles to 500K cycles Changed Data Retention from 100 years to 20 years Added Soft Sequence Processing Time Waveform Updated Part Numbering Nomenclature and Ordering Information Added RTC Characteristics Table Added RTC Recommended Component Configuration
*C	503277	See ECN	PCI	Changed from "Advance" to "Preliminary" Changed the term "Unlimited" to "Infinite" Changed endurance from 500K cycles to 200K cycles Device operation: Tolerance limit changed from +20% to +15% in the Features Section and Operating Range Table Removed Icc1 values from the DC table for 25 ns and 35 ns industrial grade Changed V _{SWITCH(min)} from 2.55V to 2.45V Added temperature specifications to data retention - 20 years at 55°C Updated Part Nomenclature Table and Ordering Information Table
*D	597004	See ECN	TUP	Removed $V_{SWITCH(min)}$ specification from AutoStore/Power Up RECALL table Changed t_{GLAX} specification from 20 ns to 1 ns Added $t_{DELAY(max)}$ specification of 70 μ s in the Hardware STORE Cycle table Removed t_{HLBL} specification Changed t_{SS} specification from 70 μ s(min) to 70 μ s(max) Changed $V_{CAP(max)}$ from 57 μ F to 120 μ F
*E	696097	See ECN	VKN	Added footnote 7 related to HSB Added footnote 8 related to INT pin Changed t _{GLAX} to t _{GHAX} Removed ABE bit from Interrupt register
*F	1349963	See ECN	UHA/SFV	Changed from Preliminary to Final Added Note 5 regarding the W bit in the Flag register Updated Ordering Information Table
*G	2483006	See ECN	GVCH/PY RS	Changed tolerance from +15%, -10% to +20%, -10% Changed Operating voltage range from 2.7V-3.45V to 2.7V-3.6V

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